National Semiconductor

August 1998

54ACTQ827
Quiet Series 10-Bit Buffer/Line Driver with TRI-STATE® Outputs

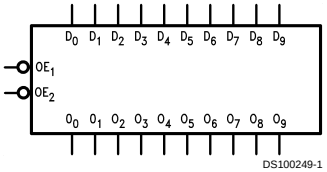
General Description

The 'ACTQ827 10-bit bus buffer provides high performance bus interface buffering for wide data/address paths or buses carrying parity. The 10-bit buffers have NOR output enables for maximum control flexibility. The 'ACTQ827 utilizes NSC Quiet Series technology to guarantee quiet output switching and improved dynamic threshold performance. FACT Quiet Series™ feature GTO™ output control and undershoot corrector in addition to a split ground bus for superior performance.

Features

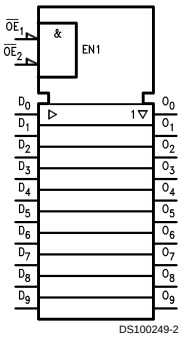
- Guaranteed simultaneous switching noise level and dynamic threshold performance
- Inputs and outputs on opposite sides of package allow easy interface with microprocessors
- Improved latch-up immunity
- Outputs source/sink 24 mA
- Functionally and pin-compatible to AMD's AM29827
- 'ACTQ827 has TTL-compatible inputs
- 4 kV minimum ESD immunity
- Standard Microcircuit Drawing (SMD) 5962-92199

Logic Symbols



DS100249-1

IEEE/IEC

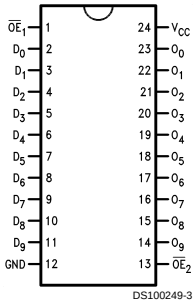


DS100249-2

Pin Names	Description
$\overline{OE}_1$, $\overline{OE}_2$	Output Enable
D_0–D_9	Data Inputs
O_0–O_9	Data Outputs

Connection Diagrams

Pin Assignment for DIP and Flatpak



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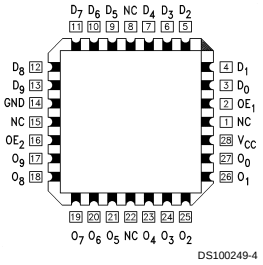
Pin Assignment for LCC



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FACT® is a registered trademark of Fairchild Semiconductor Corporation.
FACT Quiet Series™ is a trademark of Fairchild Semiconductor Corporation.

Functional Description

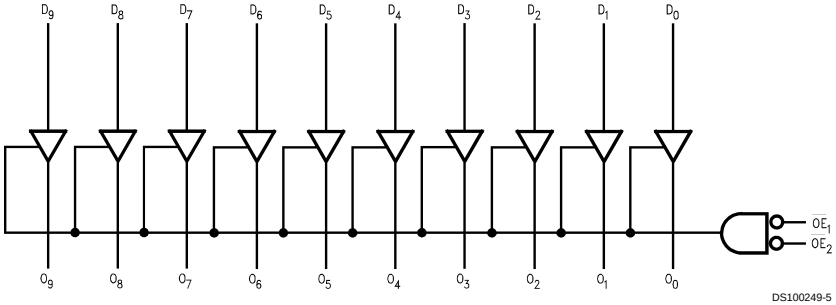
The 'ACTQ827 line driver is designed to be employed as memory address driver, clock driver and bus-oriented transmitter/receiver. The devices have TRI-STATE outputs controlled by the Output Enable ($\overline{OE}$) pins. When the $\overline{OE}$ is LOW, the device is transparent. When $\overline{OE}$ is HIGH, the device is in TRI-STATE mode.

Function Table

Inputs		Outputs	Function
$\overline{OE}$	D_n	O_n	
L	H	H	Transparent
L	L	L	Transparent
H	X	Z	High Z

H = HIGH Voltage Level
L = LOW Voltage Level
Z = HIGH Impedance
X = Immaterial

Logic Diagram



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Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

Absolute Maximum Ratings (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/ Distributors for availability and specifications.

Supply Voltage (V_{CC})	−0.5V to +7.0V
DC Input Diode Current (I_{IK})	
V_I = −0.5V	−20 mA
V_I = V_{CC} + 0.5V	+20 mA
DC Input Voltage (V_I)	−0.5V to V_{CC} + 0.5V
DC Output Diode Current (I_{OK})	
V_O = −0.5V	−20 mA
V_O = V_{CC} + 0.5V	+20 mA
DC Output Voltage (V_O)	−0.5V to V_{CC} + 0.5V
DC Output Source or Sink Current (I_O)	±50 mA
DC V_{CC} or Ground Current per Output Pin (I_{CC} or I_{GND})	±50 mA
Storage Temperature (T_{STG})	−65˚C to +150˚C
DC Latch-Up Source or Sink Current	±300 mA
Junction Temperature (T_J)	
CDIP	175˚C

Recommended Operating Conditions

Supply Voltage (V_{CC})	
'ACTQ	4.5V to 5.5V
Input Voltage (V_I)	0V to V_{CC}
Output Voltage (V_O)	0V to V_{CC}
Operating Temperature (T_A)	
54ACTQ	−55˚C to +125˚C
Minimum Input Edge Rate ΔV/Δt	
'ACTQ Devices	
V_{IN} from 0.8V to 2.0V	
V_{CC} @ 4.5V, 5.5V	125 mV/ns

Note 1: Absolute maximum ratings are those values beyond which damage to the device may occur. The databook specifications should be met, without exception, to ensure that the system design is reliable over its power supply, temperature, and output/input loading variables. National does not recommend operation of FACT® circuits outside databook specifications.

Note 2: All commercial packaging is not recommended for applications requiring greater than 2000 temperature cycles from −40˚C to +125˚C.

DC Electrical Characteristics for 'ACTQ Family Devices

Symbol	Parameter	V_{CC} (V)	54ACTQ T_A = −55˚C to +125˚C Guaranteed Limits	Units	Conditions
V_{IH}	Minimum High Level Input Voltage	4.5 5.5	2.0 2.0	V	V_{OUT} = 0.1V or V_{CC} − 0.1V
V_{IL}	Maximum Low Level Input Voltage	4.5 5.5	0.8 0.8	V	V_{OUT} = 0.1V or V_{CC} − 0.1V
V_{OH}	Minimum High Level Output Voltage	4.5 5.5	4.4 5.4	V	I_{OUT} = −50 μA
					(Note 3) V_{IN} = V_{IL} or V_{IH}
		4.5	3.70	V	I_{OH} = −24 mA
		5.5	4.70		I_{OH} = −24 mA
V_{OL}	Maximum Low Level Output Voltage	4.5 5.5	0.1 0.1	V	I_{OUT} = 50 μA
					(Note 3) V_{IN} = V_{IL} or V_{IH}
		4.5	0.50	V	I_{OL} = 24 mA
		5.5	0.50		I_{OL} = 24 mA
I_{IN}	Maximum Input Leakage Current	5.5	±1.0	μA	V_I = V_{CC}, GND
I_{OZ}	Maximum TRI-STATE Current	5.5	±10.0	μA	V_I = V_{IL}, V_{IH} V_O = V_{CC}, GND
I_{CCT}	Maximum I_{CC}/Input	5.5	1.6	mA	V_I = V_{CC} − 2.1V
I_{OLD}	(Note 4) Minimum Dynamic	5.5	50	mA	V_{OLD} = 1.65V Max
I_{OHD}	Output Current	5.5	−50	mA	V_{OHD} = 3.85V Min
I_{CC}	Maximum Quiescent Supply Current	5.5	160.0	μA	V_{IN} = V_{CC} or GND (Note 5)

DC Electrical Characteristics for 'ACTQ Family Devices (Continued)

Symbol	Parameter	V_{CC} (V)	54ACTQ $T_A = -55^\circ C$ to $+125^\circ C$ Guaranteed Limits	Units	Conditions
V_{OLP}	Quiet Output Maximum Dynamic V_{OL}	5.0	1.5	V	(Notes 6, 7)
V_{OLV}	Quiet Output Minimum Dynamic V_{OL}	5.0	−1.2	V	(Notes 6, 7)

Note 3: All outputs loaded; thresholds on input associated with output under test.

Note 4: Maximum test duration 2.0 ms, one output loaded at a time.

Note 5: I_{CC} for 54ACTQ @ 25°C is identical to 74ACTQ @ 25°C.

Note 6: Plastic DIP package.

Note 7: Max number of outputs defined as (n). Data inputs are driven 0V to 3V. One output @ GND.

Note 8: Max number of data inputs (n−1) inputs switching 0V to 3V ('ACTQ). Input-under-test switching: 3V to threshold (V_{ILD}), 0V to threshold. (V_{IHD}), f = 1 MHz.

AC Electrical Characteristics

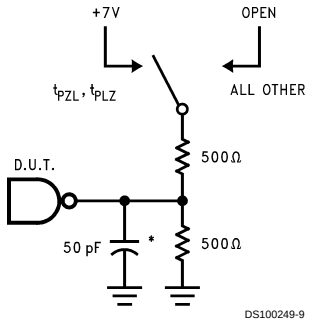
Symbol	Parameter	V_{CC} (V) (Note 9)	54ACTQ $T_A = -55^\circ C$ to $+125^\circ C$ $C_L = 50$ pF		Units
			Min	Max	
t_{PHL}, t_{PLH}	Propagation Delay Data to Output	5.0	2.0	9.0	ns
t_{PZL}, t_{PZH}	Output Enable Time	5.0	2.0	12.5	ns
t_{PHZ}, t_{PLZ}	Output Disable Time	5.0	1.0	9.0	ns

Note 9: Voltage Range 5.0 is 5.0V ±0.5V.

Capacitance

Symbol	Parameter	Typ	Units	Conditions
C_{IN}	Input Capacitance	4.5	pF	V_{CC} = OPEN
C_{PD}	Power Dissipation Capacitance	82	pF	V_{CC} = 5.0V

AC Loading



*Includes jig and probe capacitance

FIGURE 1. Standard AC Test Load

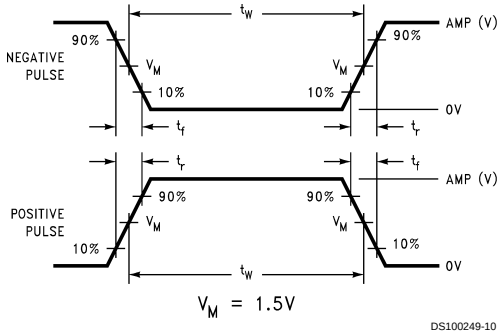


FIGURE 2. Test Input Signal Levels

Amplitude	Rep. Rate	t_w	t_r	t_f
3.0V	1 MHz	500 ns	2.5 ns	2.5 ns

FIGURE 3. Test Input Signal Requirements

AC Waveforms

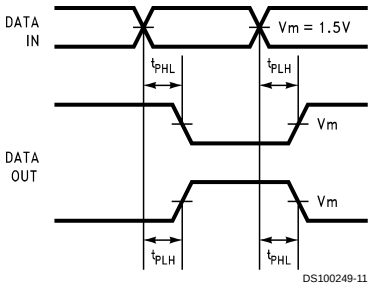


FIGURE 4. Propagation Delay Waveforms for Inverting and Non-Inverting Functions

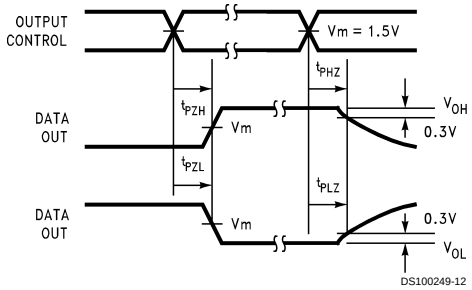
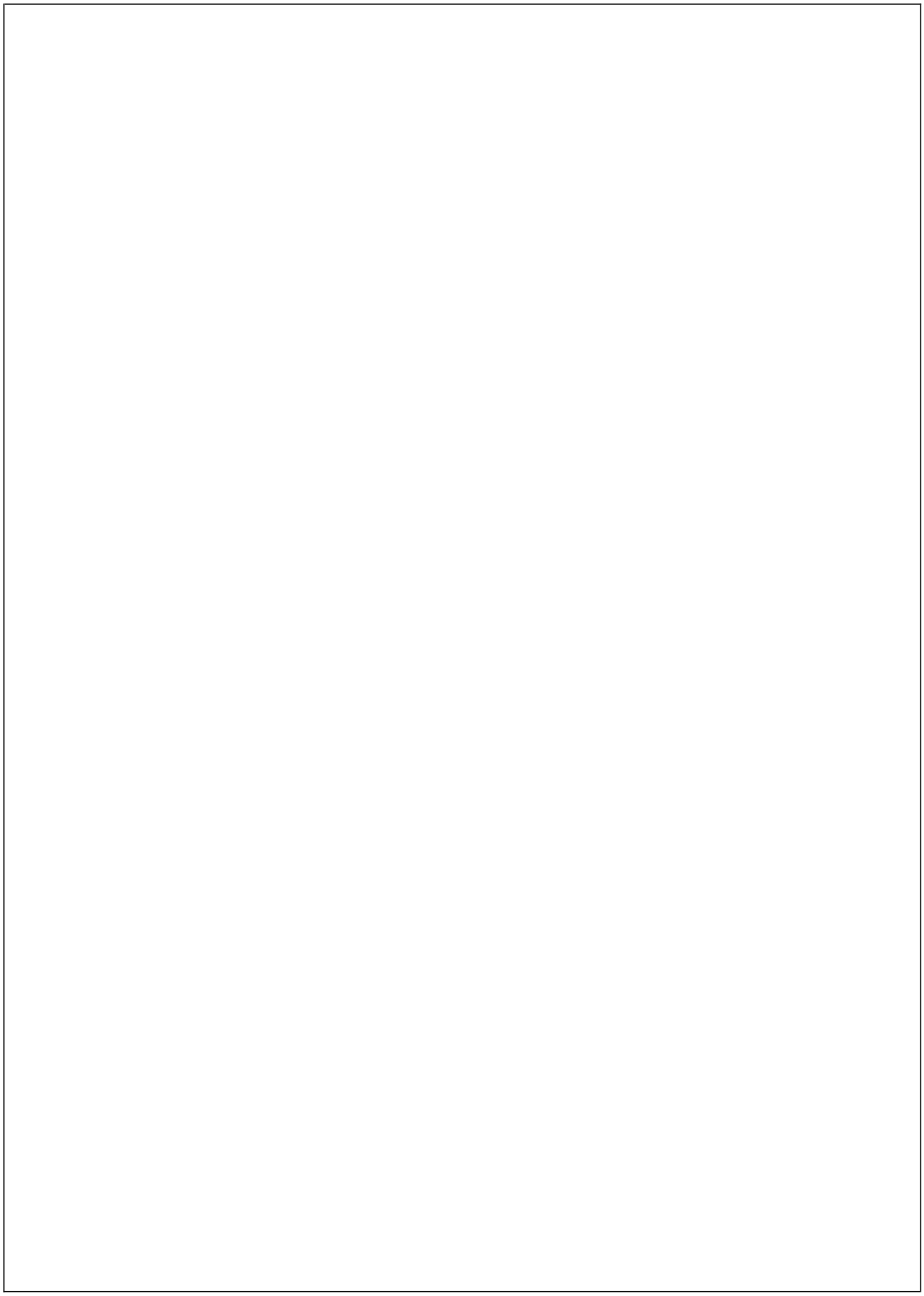
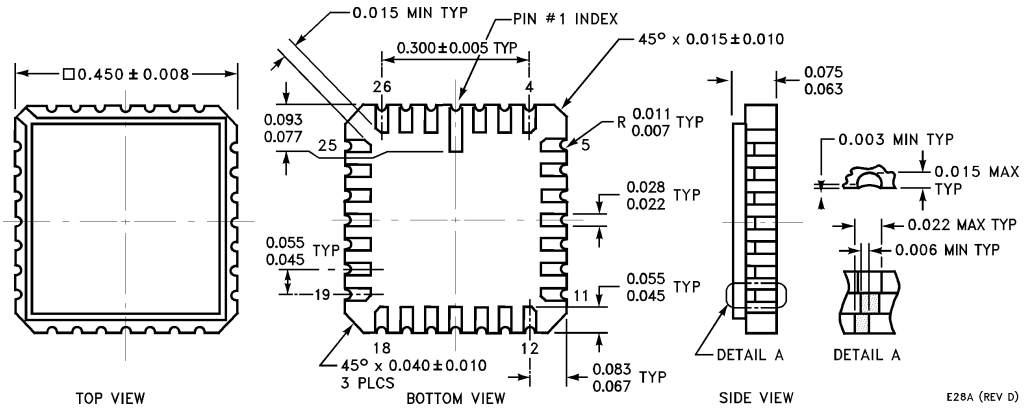


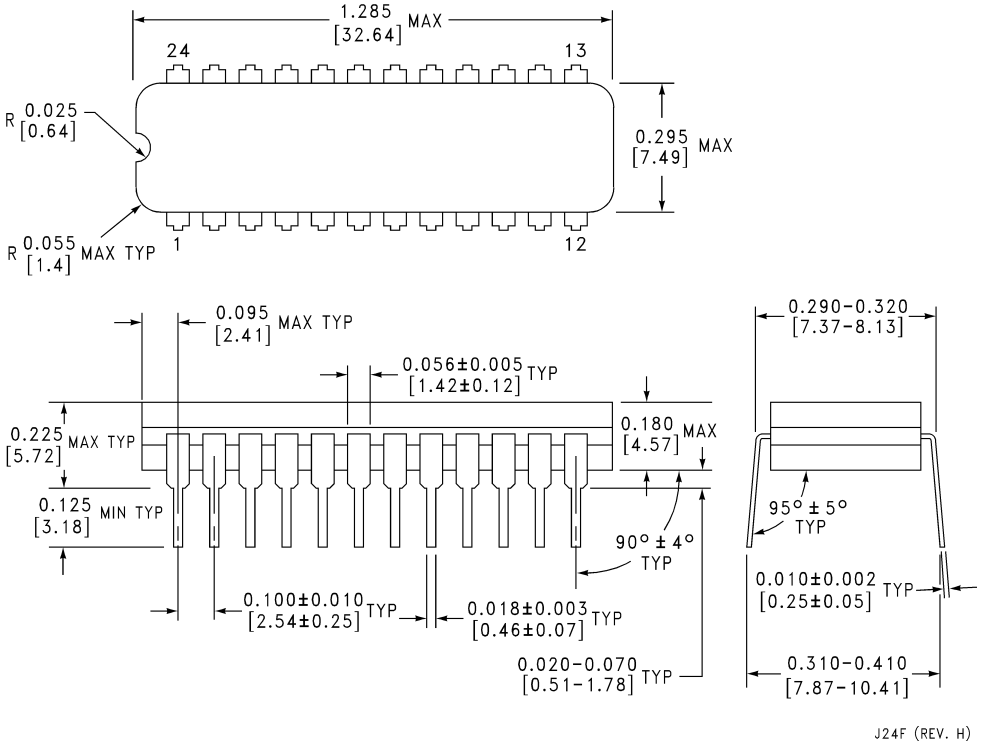
FIGURE 5. TRI-STATE Output HIGH and LOW Enable and Disable Time



Physical Dimensions inches (millimeters) unless otherwise noted

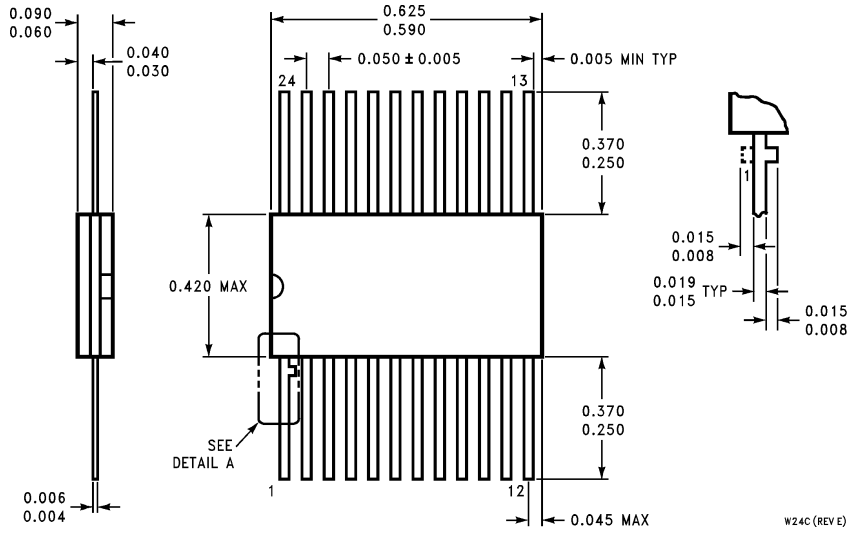


28-Terminal Ceramic Leadless Chip Carrier (L)
NS Package Number E28A



24-Lead Slim (0.300" Wide) Ceramic Dual-In-Line Package (SD)
NS Package Number J24F

Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



24 Lead Ceramic Flatpak (F)
NS Package Number W24C

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